Results of J1 VIIRS testing using NIST's Traveling SIRCUS

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RSR analysis: David Moyer Polarization analysis: Jeff McIntire

T-SIRCUS Operation: Keith Lykke, Steve Brown, Brendan McAndrew, Joel McCorkel Raytheon Interface: TR Wang

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T-SIRCUS JPSS-1 VIIRS Testing

Absolute Spectral Response of VIIRS Vis/NIR Channels Polarization Testing of Channels M1&M4

- T-SIRCUS from SNPP VIIRS to J1 VIIRS
- Responsivity Test setup
 - ASR/RSR Acquisition and Analysis
- Polarization Test Setup
 - Acquisition and Analysis

From SNPP VIIRS (2010) to J1 VIIRS (2014/15)

- SNPP VIIRS measurements at Ball Aerospace, Boulder CO
- J1 VIIRS measurements at Raytheon, El Segundo, CA



Radiance responsivity through the Earth-view (Nadir-view) port Solar irradiance through the Solar Port

T-SIRCUS&SNPP VIIRS: The Good

Full aperture illumination v piece-parts characterization and calibration approach



David Moyer, Aerospace Corp

- Reduced wavelength uncertainty
 - More accurate band-center wavelength determination
- Better characterization of detector-to-detector differences at the focal plane
- Absolute uncertainty ~0.5 %

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 meets the stringent ocean color calibration uncertainty requirements.

T-SIRCUS&SNPP VIIRS: The Bad Laser issues



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J1 VIIRS T-SIRCUS Raytheon Test Setup Improved capabilities over SNPP measurements

- 1. New LBO OPO system
 - Higher Power, Automated Tuning over the full spectral range

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- Approx 10 s per step; 5 s or less for fine steps
- 2. Tunable Dye Lasers (DCM and R6G)
 - Higher Power, Automated Tuning
 - Approx 5 s per step
 - Fill in 560 nm to 670 nm spectral region
- 3. New Calibration Sources
 - 1-m Spectralon* coated integrating sphere

*Spectralon is a product of LabSphere, Inc.

1. Development of T-SIRCUS LBO OPO System Developed by Keith Lykke, NIST



Rotation Stage* (Prism Angle) LBO Crystal Oven*

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Pump Laser

*under computer control

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Benefits: Higher Power, Automated Tuning

Temperature

Prism-tuned OPO Control Curves





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LBO OPO Doubler Path

Doubling now computer-controlled as well



Rotary Stages (computer controlled)

Adjust the angle of the doubling crystal Adjust the angle of a compensator to keep the path the same

T-SIRCUS LBO OPO Tuning Curve

Gap filled in with Doubled OPO Idler Signal and/or Dye Lasers



At the time we were not doubling the Idler Signal

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Used cw dye lasers to fill in the GAP

2. Include dye laser with DCM and R6G dyes

Dye laser table

- 2 ft x 6 ft table
 - Pump laser
 - Ti:S laser
 - Dye Laser

Doubling System
Dyes we used at Raytheon
R6G: 565 nm to 615 nm
DCM: 610 nm to 680 nm



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Tuning Curve LBO OPO w/ Dye Laser Dye lasers under computer control



Wavelength [nm]

3. 1-m Spectralon SpIS Radiometric Properties Operational Characteristics Radiance Out to Laser Power In



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Path to radiometric traceability





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Sphere monitor calibration 16-17 Dec 2014



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Joel McCorkel



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Joel McCorkel

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QuickLook J1 VIIRS Test Results

- RSR
 - David Moyer, Frank DeLuccia, and Janna Feeley

- Manuscript in preparation, Joel McCorkel
- Polarization dependence of the sensor
 - Jeff McIntire, Gene Waluschka
 - SPIE presentations by both



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Detector-to-detector Differences



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Centroid Wavelength for Bands M5 & M6 Calculated using SIRCUS and SpMA approaches

Band M5 Band M6 669 746.8 Centroid Wavelength [nm] SIRCUS Centroid Wavelength [nm] 746.6 668.5 SIRCUS SpMA 746.4 SpMA ∆ ≈ 0.5 nm 668 746.2 ∆ ≈ 1.2 nm 746 667.5 745.8 667 745.6 745.4 666.5 15 5 10 15 5 10 0 0 Detector Detector

SIRCUS – Blue symbols SpMA – Red Symbols

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Polarization Testing

Polarizer and SIS tested at NIST prior to measurements.



Measured DOLP at a number of scan angles, both HAM sides Mapped out DOLP for Bands M1 and M4

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Degree of Linear Polarization v Wavelength +45 deg scan angle, HAM side 1



Summary

- General consensus is that the measurements went well.
 - Uncertainty in the SIS radiance 0.2 % or less (typically)
 - Good measure of band-center wavelength, detector-todetector differences
 - Cross-talk again determined to be a small effect
 - Band ASRs (IB) uncertainty ~0.25 % or less; 5 decades OOB dynamic range
 - Observed unpredicted features in DOLP tests of Band M4
- As I understand it, T-SIRCUS measurements are planned for J2
 - Could be either the NIST T-SIRCUS or a NASA Goddard T-SIRCUS

Acknowledge Bruce Guenther, NOAA/NASA/Stellar Solutions for initiating and pushing for the T-SIRCUS measurements on SNPP VIIRS

One common response: You want to shoot lasers at VIIRS? You have to be kidding me!

> Boeing's Matrix Laser destroying an Air Drone



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Additional Slides

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FPI Radiometric Properties





Operational Characteristics Power In to Radiance Out

One arm illuminated@532 nm (Camera not focused at infinity)



Input power to radiance conversion L= 1.6 [W/m²/sr]/mW @ 532 nm

Note: FPI could potentially be used in TVAC at BATC to calibrate VIIRS NIR channels 2

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FPI Radiometric Properties





Operational Characteristics Power In to Radiance Out

One arm illuminated@532 nm (Camera not focused at infinity)



Input power to radiance conversion L= 1.6 [W/m²/sr]/mW @ 532 nm

Note: FPI could potentially be used in TVAC at BATC to calibrate VIIRS NIR channels 30

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Compare efficiencies of SIS and FPI @ 532 nm

FPI

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3.2 Radiance/Input Laser Power [(W/m²/sr)/W] 3 2.8 2.6 ۲ 2.4 2.2 800 400 500 600 700 900 Wavelength [nm]

 $L= 2.8 [W/m^2/sr]/W$

- $L= 1.6 [W/m^2/sr]/mW$
- At 532 nm, FPI is approx. 500 times more efficient than the 1-m Spectralon SIS in converting Input Power to Radiance.
- For consideration: 500 mW into the SIS gives a reasonable signal for VIIRS to read. The corresponding power into the FPI is 1 mW.
- Efficient power to radiance transfer coefficient opens up other possibilities with the FPI. Lots of sources can give you 1 mW (think Supercontinuum sources or Laserdriven Arc Sources).

1-m SIS